Metal contacts in TFTs

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In a previous work, a model for thin-film field-effect transistors (TFTs) was developed. One of the issues not addressed in that model is the effect of the contacts.

Conventionally, (organic) TFTs are analyzed with the standard MOS-FET model. In a MOS-FET, the contacts are pn-junctions (p-type and n-type same-material junctions) but TFTs normally have metallic electrodes.

Attempts for MOS-FETs with metallic contacts have been made to model them with Schottky barriers or the generic term "contact resistance" to describe any deviations from standard MOS-FET theory.

Diodes (pn-junctions or Schottky barriers) do not make sense when the active layer is two-dimensional (TFTs).

Diodes or resistances cannot explain non-linear effects (see Figure). Non-linear effects of curves can easily be explained by traps.

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Traps!



Schottky TFT The above figure (right) shows why Schottky barrier (or pn junction) analysis is less adequate for TFTs: In a Schottky barrier the dimensions perpendicular to current (x,z)can be imagined to stretch to infinity and Poisson's Equation can be

applied: $d^2 V(x)/dx^2 = (x)$ In a TFT, only one direction (z) is infinite. Poisson's Equation cannot be applied

Sometimes also the generic term "contact resistance" is used to explain any deviations from standard MOS-FET theory. Simulations of these elements (see right panel) show simulations.







